

**Notice of References Cited**Application/Control No.  
**09/873,264**Applicant(s)/Patent Under Reexam  
**Uchida et al.**Examiner  
**B. William Baumeister**Art Unit  
**2815**

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<sup>1</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.